Preferred Device

Sensitive Gate Silicon Controlled Rectifiers

Reverse Blocking Thyristors

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

Features

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and Holding Characteristics
- Available in Two Package Styles Surface Mount Lead Form – Case 369C Miniature Plastic Package – Straight Leads – Case 369
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Human Body Model, 3B > 8000 V Machine Model, C > 400 V
- Pb–Free Packages are Available

MAXIMUM RATINGS (T_J = 25° C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (T _J = -40 to 110°C, Sine Wave, 50 Hz to 60 Hz) MCR8DSM MCR8DSN	V _{DRM,} V _{RRM}	600 800	V
On–State RMS Current (180° Conduction Angles; $T_C = 90$ °C)	I _{T(RMS)}	8.0	A
Average On-State Current (180° Conduction Angles; T _C = 90°C)	I _{T(AV)}	5.1	A
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T _J = 110°C)	I _{TSM}	90	A
Circuit Fusing Consideration (t = 8.3 msec)	l ² t	34	A ² sec
Forward Peak Gate Power (Pulse Width \leq 10 μ sec, T _C = 90°C)	P _{GM}	5.0	W
Forward Average Gate Power (t = 8.3 msec, T_C = 90°C)	P _{G(AV)}	0.5	W
Forward Peak Gate Current (Pulse Width \leq 10 μ sec, T _C = 90°C)	I _{GM}	2.0	A
Operating Junction Temperature Range	TJ	-40 to 110	°C
Storage Temperature Range	T _{stg}	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

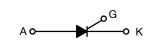
 V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for negative gate voltage; positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the device are exceeded.



ON Semiconductor®

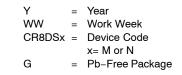
http://onsemi.com

SCRs 8 AMPERES RMS 600 – 800 VOLTS



MARKING DIAGRAM





PIN ASSIGNMENT			
1	Cathode		
2	Anode		
3	Gate		
4	Anode		

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

Preferred devices are recommended choices for future use and best overall value.

Semiconductor Components Industries, LLC, 2008 November, 2008 – Rev. 5

THERMAL CHARACTERISTICS

Characteristic		Symbol		Max		Unit
Thermal Resistance – Junction-to-Case – Junction-to-Ambient – Junction-to-Ambient (Note 2)		R _{θJC} R _{θJA} R _{θJA}	2.2 88 80			°C/W
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 10 Seconds		TL	260		°C	
ELECTRICAL CHARACTERISTICS (T _J = 25°C unless	s otherwise noted)					
Characteristics		Symbol	Min	Тур	Max	Unit
DFF CHARACTERISTICS						
Peak Repetitive Forward or Reverse Blocking Current (V_{AK} = Rated V_{DRM} or V_{RRM} ; R_{GK} = 1.0 k Ω) (Note 3)	T _J = 25°C T _J = 110°C	I _{DRM} I _{RRM}	-	_	10 500	μA
ON CHARACTERISTICS						
Peak Reverse Gate Blocking Voltage (I_{GR} = 10 μ A)		V _{GRM}	10	12.5	18	V
Peak Reverse Gate Blocking Current (V _{GR} = 10 V)		I _{RGM}	-	-	1.2	μA
Peak Forward On-State Voltage (Note 4) (I _{TM} = 16 A)		V _{TM}	-	1.4	1.8	V
Gate Trigger Current (Continuous dc) (Note 5) $(V_D = 12 \text{ V}, \text{ R}_L = 100 \Omega)$	T _J = 25°C T _J = -40°C	I _{GT}	5.0 -	12 -	200 300	μΑ
Gate Trigger Voltage (Continuous dc) (Note 5) $(V_D = 12 \text{ V}, \text{ R}_L = 100 \Omega)$	$T_J = 25^{\circ}C$ $T_J = -40^{\circ}C$ $T_J = 110^{\circ}C$	V _{GT}	0.45 _ 0.2	0.65 _ _	1.0 1.5 -	V
Holding Current (V _D = 12 V, Initiating Current = 200 mA, R _{GK} = 1 k Ω)	$T_J = 25^{\circ}C$ $T_J = -40^{\circ}C$	Ι _Η	0.5 _	1.0 -	6.0 10	mA
Latching Current (V _D = 12 V, I _G = 2.0 mA, R _{GK} = 1 kΩ)	$T_J = 25^{\circ}C$ $T_J = -40^{\circ}C$	١L	0.5	1.0 _	6.0 10	mA
Total Turn–On Time (Source Voltage = 12 V, $R_S = 6.0 \text{ k}\Omega$, $I_T = 16 \text{ A(pk)}$, R_{Gi} ($V_D = \text{Rated } V_{DRM}$, Rise Time = 20kns, Pulse Width = 7	,	tgt	_	2.0	5.0	μs

Critical Rate of Rise of Off-State Voltage	dv/dt				V/μs
(V _D = 0.67 X Rated V _{DRM} , Exponential Waveform,		2.0	10	-	
$R_{GK} = 1.0 \text{ k}\Omega, T_{J} = 110^{\circ}\text{C}$					

2. Surface mounted on minimum recommended pad size.

3. Ratings apply for negative gate voltage or $R_{GK} = 1.0 \text{ k}\Omega$. Devices shall not have a positive gate voltage concurrently with a negative voltage on the anode. Devices should not be tested with a constant current source for forward and reverse blocking capability such that the voltage applied exceeds the rated blocking voltage.

4. Pulse Test; Pulse Width \leq 2.0 msec, Duty Cycle \leq 2%. 5. R_{GK} current not included in measurements.

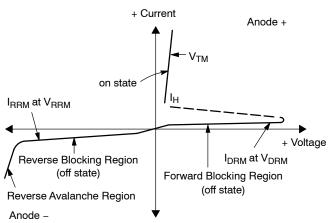
ORDERING INFORMATION

Device	Package	Shipping [†]
MCR8DSMT4	DPAK	
MCR8DSMT4G	DPAK (Pb-Free)	0500 / Terra & Deel
MCR8DSNT4	DPAK	2500 / Tape & Reel
MCR8DSNT4G	DPAK (Pb–Free)	

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Voltage Current Characteristic of SCR

Symbol	Parameter
V _{DRM}	Peak Repetitive Off-State Forward Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Off-State Reverse Voltage
I _{RRM}	Peak Reverse Blocking Current
V _{TM}	Peak On-State Voltage
I _H	Holding Current



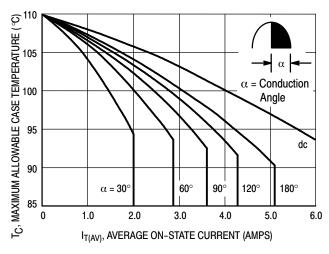


Figure 1. Average Current Derating

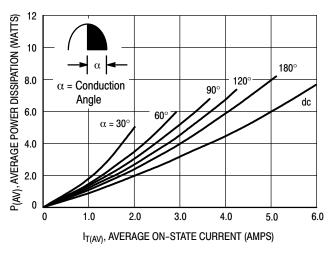
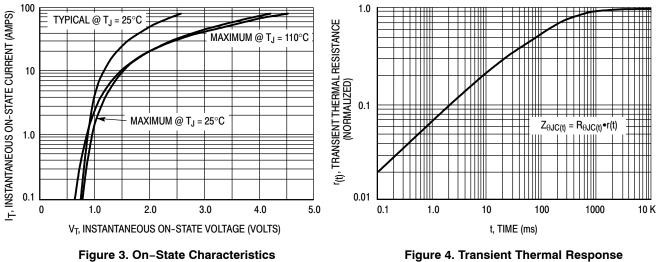


Figure 2. On-State Power Dissipation



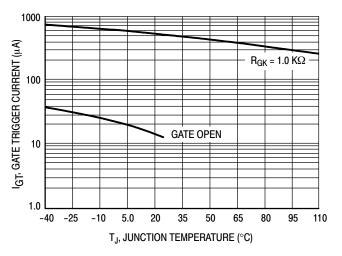
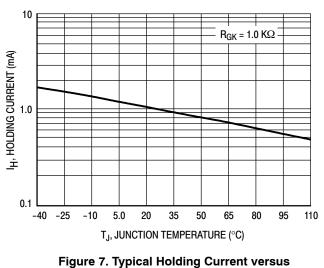


Figure 5. Typical Gate Trigger Current versus **Junction Temperature**



Junction Temperature

Figure 4. Transient Thermal Response

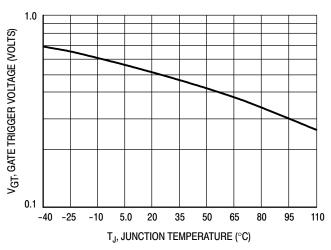


Figure 6. Typical Gate Trigger Voltage versus **Junction Temperature**

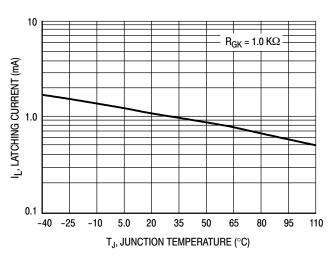
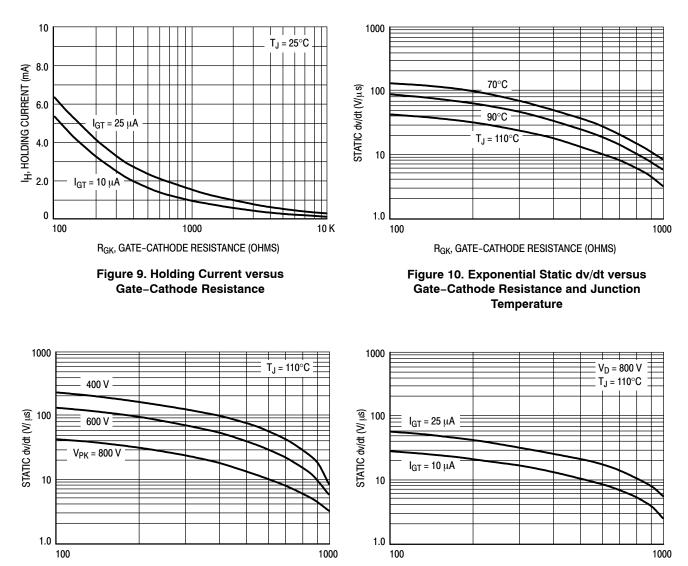


Figure 8. Typical Latching Current versus Junction Temperature



R_{GK}, GATE-CATHODE RESISTANCE (OHMS)

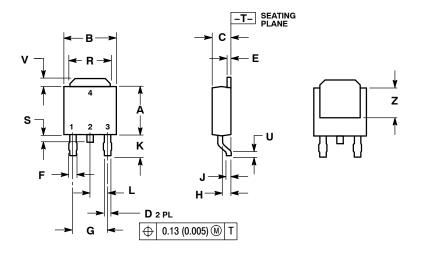
Figure 11. Exponential Static dv/dt versus Gate-Cathode Resistance and Peak Voltage

R_{GK}, GATE-CATHODE RESISTANCE (OHMS)

Figure 12. Exponential Static dv/dt versus Gate–Cathode Resistance and Gate Trigger Current Sensitivity

PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE) CASE 369C-01 **ISSUE A**



2. CONTROLLING DIMENSION: INCH. INCHES MILLIMETERS DIM MIN MAX MIN MAX A 0.235 0.245 5.97 6.22 в 0.250 0.265 6.35 6.73 **C** 0.086 0.094 2.19 2.38 **D** 0.027 0.035 0.69 0.88 0.018 0.023 Е 0.46 0.58 **F** 0.037 0.045 0.94 1.14 G 0 180 BSC 4 58 BSC H 0.034 0.040 0.87 1.01 J 0.018 0.023 0.46 0.58 κ 0.102 0.114 2.60 2.89 2.29 BSC L 0.090 BSC R 0.180 0.215 4.57 5.45 S 0.025 0.040 0.63 1.01 U 0.020 V 0.035

0.050

0.51

0.89

3.93

1.27

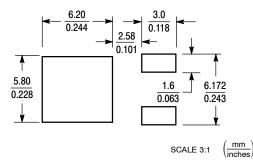
DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

STYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE 4 ANODE

Z 0.155

NOTES

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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